## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination YAGUCHI ET AL. | Examiner | Art Unit | John L. Goodrow | 1756 | Page 1 of 1 | U.S. PATENT DOCUMENTS \* | Document Number | Date | MM-YYYY | Name | Classification | Country Code-Number-Kind Code | MM-YYYYY | Name | Classification |

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